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Application/Control No.	Applicant(s)/Patent under Reexamination
10/595,344	HAARTSEN, JACOBUS
Examiner	Art Unit
TUAN A. PHAM	2618

SEARCHED			
Class	Subclass	Date	Examiner
455	133	2/14/2007	PHAM
	272		
	277.1		
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370	401		
	409	2/15/2007	PHAM
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INTERFERENCE SEARCHED			
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Consulted with:		
Nguyen Vo	2/15/2007	РНАМ
Steven Nguyen (Primary 370)		
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